

Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from, Europe, America and south Asia, supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

Email & Skype: info@chipsmall.com Web: www.chipsmall.com

Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China



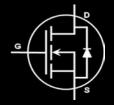




eGaN® FET DATASHEET EPC2012

EPC2012 – Enhancement Mode Power Transistor

 V_{DSS} , 200 V $\overline{R}_{DS(ON)}$, $100 \, m\Omega$ I_D , 3A

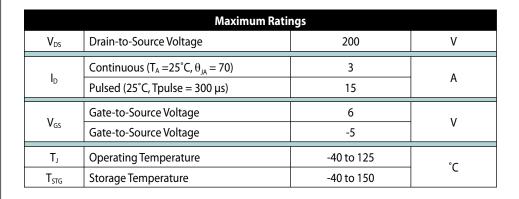








Gallium Nitride is grown on Silicon Wafers and processed using standard CMOS equipment leveraging the infrastructure that has been developed over the last 55 years. GaN's exceptionally high electron mobility and low temperature coefficient allows very low R_{DS(ON)}, while its lateral device structure and majority carrier diode provide exceptionally low Q_G and zero Q_{RR} . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.





EPC2012 eGaN® FETs are supplied only in passivated die form with solder bars

Applications

- High Speed DC-DC conversion
- · Class D Audio
- Hard Switched and High Frequency Circuits

Benefits

- · Ultra High Efficiency
- Ultra Low R_{DS(on)}
- Ultra low Q_G
- · Ultra small footprint

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT		
Static Character	Static Characteristics (T _J = 25°C unless otherwise stated)							
BV_{DSS}	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V, } I_D = 60 \mu\text{A}$ 200				V		
I _{DSS}	Drain Source Leakage	$V_{DS} = 160 \text{ V}, V_{GS} = 0 \text{ V}$		10	50	μΑ		
1	Gate-Source Forward Leakage	$V_{GS} = 5 V$		0.2	1	mA		
I_{GSS}	Gate-Source Reverse Leakage	$V_{GS} = -5 \text{ V}$		0.1	0.5			
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 1 \text{ mA}$	0.7	1.4	2.5	V		
R _{DS(ON)}	Drain-Source On Resistance	$V_{GS} = 5 \text{ V, } I_D = 3 \text{ A}$		70	100	mΩ		
Source-Drain Characteristics (T _j = 25°C unless otherwise stated)								
V_{SD}	Source-Drain Forward Voltage	$I_S = 0.5 \text{ A}, V_{GS} = 0 \text{ V}, T = 25^{\circ}\text{C}$		1.9				
		$I_S = 0.5 \text{ A}, V_{GS} = 0 \text{ V}, T = 125 ^{\circ}\text{C}$		2		<u> </u>		

All measurements were done with substrate shorted to source.

Thermal Characteristics					
		TYP			
$R_{ heta$ JC	Thermal Resistance, Junction to Case	7.6	°C/W		
$R_{\scriptscriptstyle ext{ hetaJB}}$	Thermal Resistance, Junction to Board	36	°C/W		
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1)	85	°C/W		

Note 1: $R_{\scriptscriptstyle 0JA}$ is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See http://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf for details. eGaN® FET DATASHEET EPC2012

PARAMETER		TEST CONDITIONS	MIN	ТҮР	MAX	UNIT		
Dynamic Chara	Dynamic Characteristics (T _J = 25°C unless otherwise stated)							
C _{ISS}	Input Capacitance			128	145			
Coss	Output Capacitance	$V_{DS} = 100 V, V_{GS} = 0 V$		73	95	pF		
C _{RSS}	Reverse Transfer Capacitance			3.3	4.4			
Q_{G}	Total Gate Charge (V _{GS} = 5 V)			1.5	1.8			
Q_{GD}	Gate to Drain Charge	$V_{DS} = 100 \text{ V, } I_{D} = 3 \text{ A}$		0.57	0.75			
Q_{GS}	Gate to Source Charge			0.33	0.41	nC		
Q _{oss}	Output Charge	$V_{DS} = 100 V, V_{GS} = 0 V$		11	14			
Q_{RR}	Source-Drain Recovery Charge			0				

All measurements were done with substrate shorted to source.

Figure 1: Typical Output Characteristics

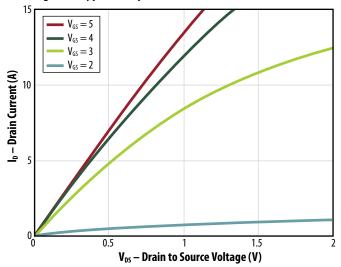


Figure 3: $R_{DS(ON)}$ vs. V_{GS} for Various Drain Currents

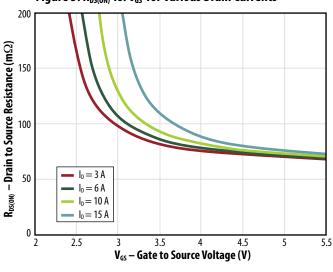


Figure 2: Transfer Characteristics

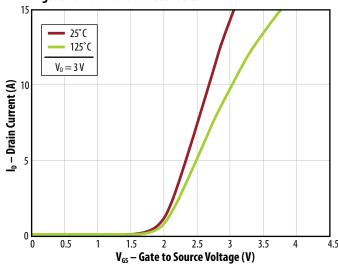
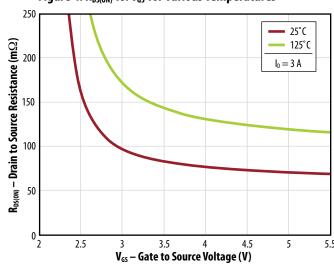
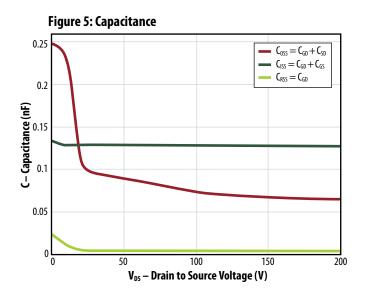
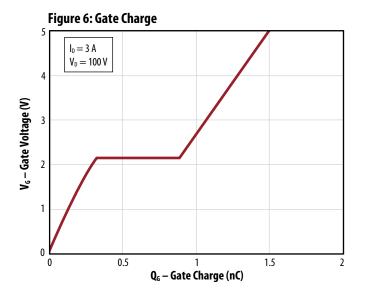


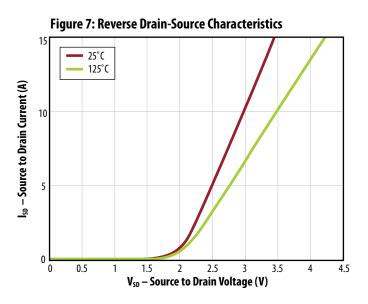
Figure 4: R_{DS(ON)} vs. V_{GS} for Various Temperatures

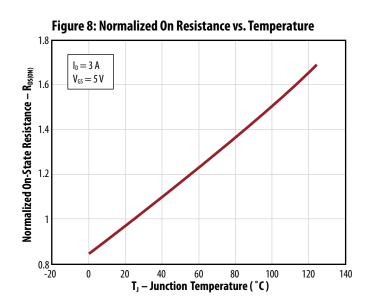


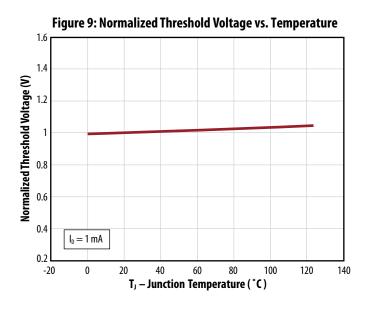
eGaN® FET DATASHEET EPC2012

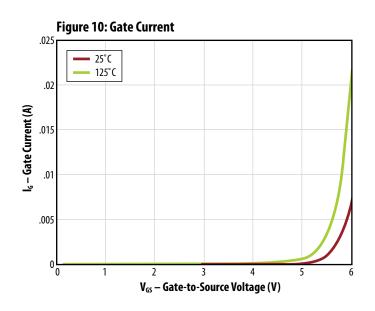








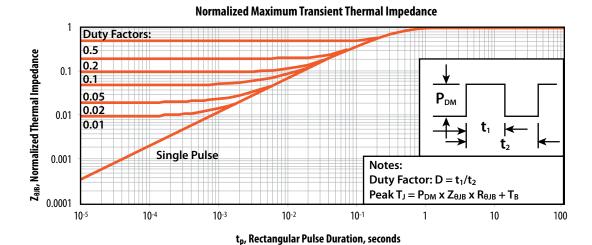




All measurements were done with substrate shortened to source.

eGaN® FET DATASHEET EPC2012

Figure 11: Transient Thermal Response Curves



Normalized Maximum Transient Thermal Impedance

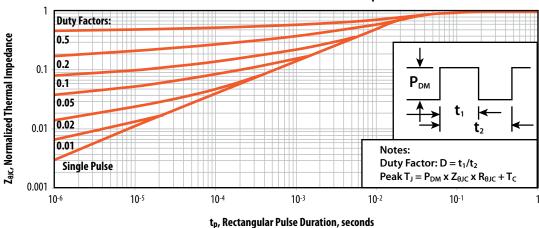
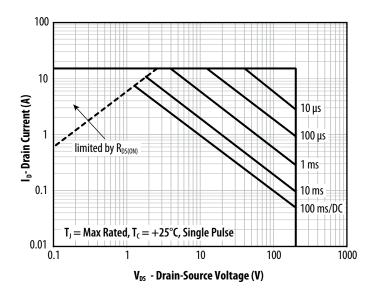
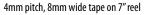


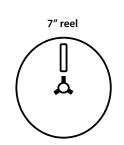
Figure 12: Safe Operating Area

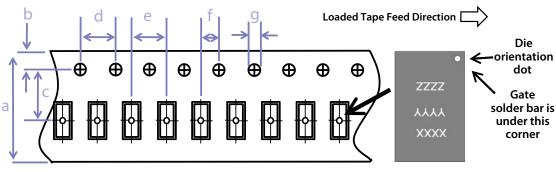


EPC2012 eGaN® FET DATASHEET

TAPE AND REEL CONFIGURATION







EPC2012 (note 1) Dimension (mm) max min target 8.00 7.90 8.30 b 1.75 1.65 1.85 c (note 2) 3.50 3.45 3.55 4.00 3.90 4.10 4.00 3.90 4.10 e f (note 2) 2.00 1.95 2.05 1.5 1.5 1.6 g

Die is placed into pocket solder bar side down (face side down)

Note 1: MSL1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

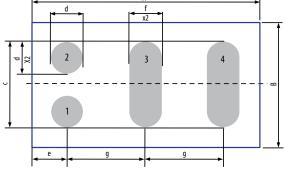
DIE MARKINGS

2012 YYYY Die orientation dot ZZZZ **Gate Pad solder bar** is under this corner

Dort	Laser Markings			
Part Number	Part # Marking Line 1	Lot_Date Code Marking line 2	Lot_Date Code Marking Line 3	
EPC2012	2012	YYYY	ZZZZ	

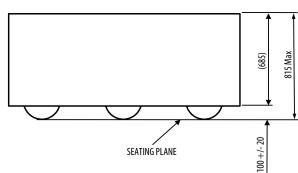
DIE OUTLINE

Solder Bar View



DIM	MILLIMETERS				
DIM	MIN	Nominal	MAX		
Α	1.681	1.711	1.741		
В	0.889	0.919	0.949		
C	0.660	0.663	0.666		
d	0.251	0.254	0.257		
e	0.230	0.245	0.260		
f	0.251	0.254	0.257		
g	0.600	0.600	0.600		

Side View

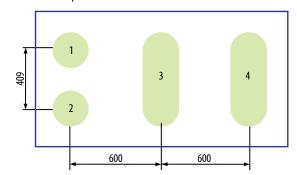


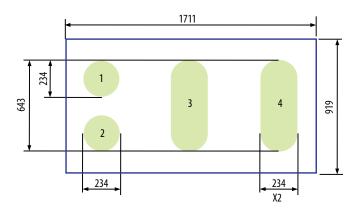
eGaN® FET DATASHEET EPC2012

RECOMMENDED LAND PATTERN

(units in µm)

The land pattern is solder mask defined





Pad no. 1 is Gate

Pad no. 2 is Substrate

Pad no. 3 is Drain

Pad no. 4 is Source

Efficient Power Conversion Corporation (EPC) reserves the right to make changes without further notice to any products herein to improve reliability, function or design. EPC does not assume any liability arising out of the application or use of any productor circuit described herein; neither does it convey any license under its patent rights, nor the rights of others. $eGaN^{\circ} \ is \ a \ registered \ trademark \ of \ Efficient \ Power \ Conversion \ Corporation.$

Information subject to change without notice. Revised October, 2012